

FQA62N25C

250V N-Channel MOSFET

General Description

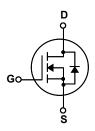
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters and switch mode power supplies.

Features

- 62A, 250V, $R_{DS(on)}$ = 0.035 Ω @V_{GS} = 10 V Low gate charge (typical 100 nC)
- Low Crss (typical 63.5 pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQA62N25C	Units
V_{DSS}	Drain-Source Voltage		250	V
I _D	Drain Current - Continuous (T _C = 25°	°C)	62	Α
	- Continuous (T _C = 100°C)		39	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	248	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	2300	mJ
I _{AR}	Avalanche Current	(Note 1)	62	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	29.8	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns
P_{D}	Power Dissipation (T _C = 25°C)		298	W
	- Derate above 25°C		2.38	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T.	T _L Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C
. L			300	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.42	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	250			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°0		0.28		V/°C
I _{DSS}		V _{DS} = 250 V, V _{GS} = 0 V			10	μΑ
	Zero Gate Voltage Drain Current	V _{DS} = 200 V, T _C = 125°C			100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 μA	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} =10 V, I _D =31 A		0.029	0.035	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 31 A (Note	4)	55		S
Dynam C _{iss}	ic Characteristics Input Capacitance	V 05 V V 0 V		4830	6280	pF
Coss	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		945	1230	рF
C _{rss}	Reverse Transfer Capacitance			63.5	83	pF
155						le.
Switchi	ng Characteristics					
t _{d(on)}	Turn-On Delay Time	V_{DD} = 125 V, I_{D} = 62 A, R_{G} = 25 Ω		75	160	ns
t _r	Turn-On Rise Time			395	800	ns
$t_{d(off)}$	Turn-Off Delay Time			245	500	ns
t _f	Turn-Off Fall Time	(Note	4)	335	680	ns
Qg	Total Gate Charge	V _{DS} = 200 V, I _D = 62 A,		100	130	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V (Note 4)		25.5		nC
Q_{gd}	Gate-Drain Charge			39		nC
Drain S	Source Diode Characteristics a	nd Maximum Patings				
I _S	Maximum Continuous Drain-Source Did	<u>~</u>			62	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				248	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 62 A			1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 62 \text{ A},$		340		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 \text{ A/}\mu\text{s} $ (Note		4.77		μС

- **Notes:** 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 0.96mH, I $_{AS}$ = 62A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C 3. I $_{SD}$ ≤ 62A, di/dt ≤ 300A/ μ s, V $_{DD}$ ≤ BV $_{DSS}$, Starting T $_{J}$ = 25°C 4. Pulse Test : Pulse width ≤ 300 μ s, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

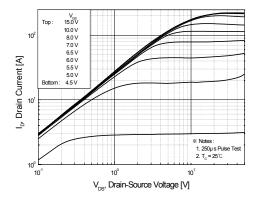


Figure 1. On-Region Characteristics

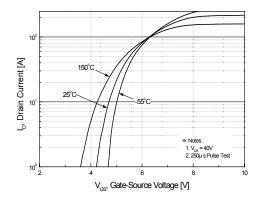


Figure 2. Transfer Characteristics

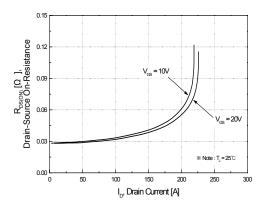


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

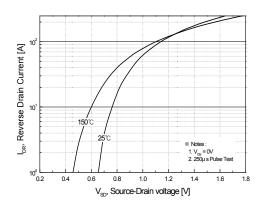


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

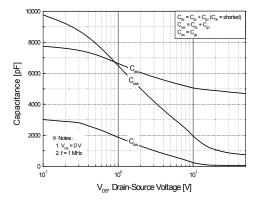


Figure 5. Capacitance Characteristics

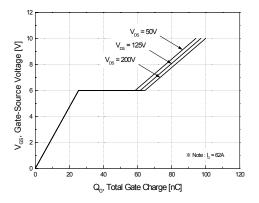


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

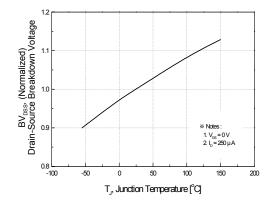


Figure 7. Breakdown Voltage Variation vs Temperature

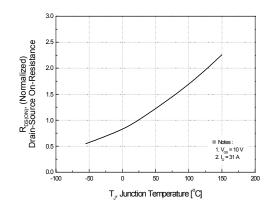


Figure 8. On-Resistance Variation vs Temperature

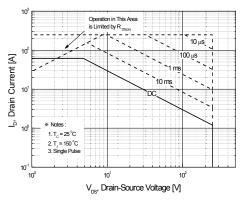


Figure 9. Maximum Safe Operating Area

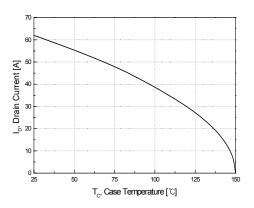


Figure 10. Maximum Drain Current vs Case Temperature

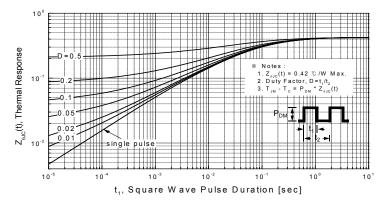
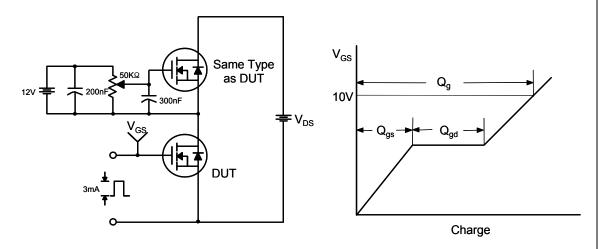


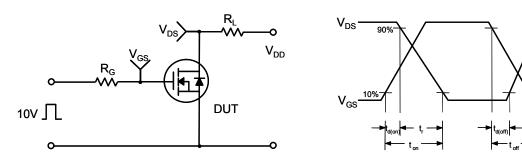
Figure 11. Transient Thermal Response Curve

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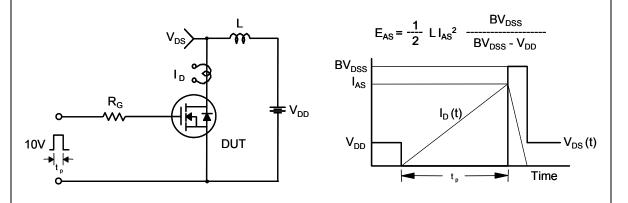
Gate Charge Test Circuit & Waveform



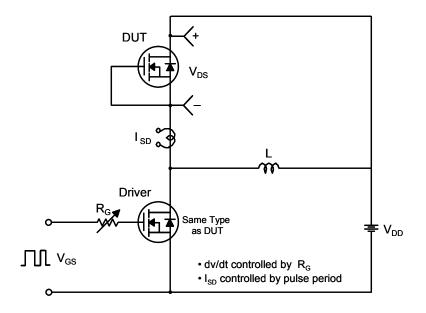
Resistive Switching Test Circuit & Waveforms

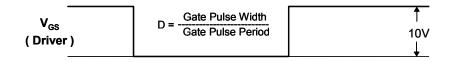


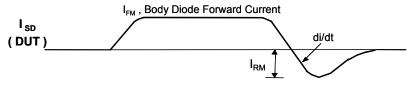
Unclamped Inductive Switching Test Circuit & Waveforms



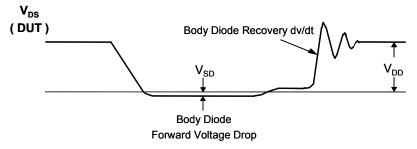
Peak Diode Recovery dv/dt Test Circuit & Waveforms





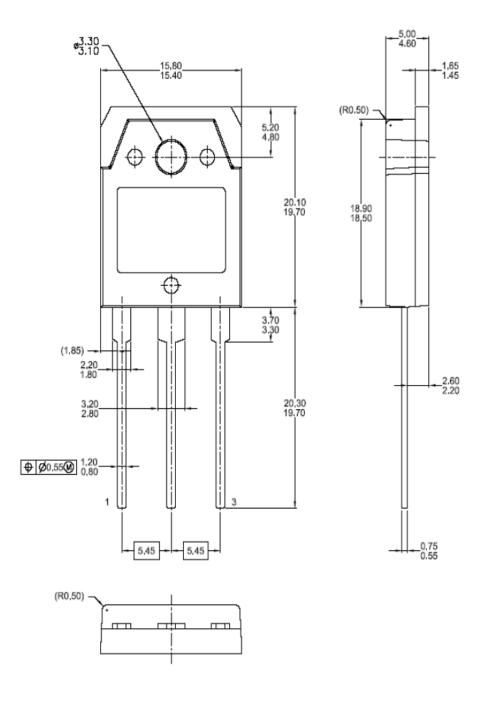


Body Diode Reverse Current



Mechanical Dimensions

TO-3PN



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